

PATENT

**IN THE UNITED STATES PATENT AND
TRADEMARK OFFICE**

Inventor:	Buxton, et al.	Docket No.:	TAI.0800
Serial No.:	10/730,388	Examiner:	Khuu, Cindy D.
Filing Date:	December 07, 2003	Art Unit:	2863
Title:	Methods and Apparatus for Data Analysis		

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner of Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Commissioner:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and pursuant to 37 C.F.R. §§1.97-1.98, the reference or references listed and identified on the attached PTO/SB/08-based form are being submitted for consideration by the Examiner.

The applicant further provides the following information for which no written references are possessed:

- The article: Variance Reduction Using Wafer Patterns, Daasch, McNames, Bockelman, Cota (2003);
- The company LSI may have a commercial SPP solution using Nearest-Neighbor Residual (NNR) technology that may be relevant; and
- Mr. Charles Meyerson of Medtronic may have information about LSI's NNR/SPP techniques that may be relevant.


Inventor: Buxton, et al.
Serial No.: 10/730,388
Filed: December 07, 2003

The preceding information and the attached references are cited only in the interest of candor and without any admission that they constitute statutory prior art or contain matter which anticipates the invention or which would render the same obvious, either singly or in combination, to a person of ordinary skill in the art.

This Information Disclosure Statement (IDS) is being filed under 37 C.F.R. §1.97(c) before the mailing date of any final action under 37 C.F.R. §1.113, a notice of allowance under 37 C.F.R. §1.311, or an action that otherwise closes prosecution of the application. The IDS is accompanied by the fee set forth in 37 C.F.R. §1.17(p). If there are any questions concerning this IDS, the Examiner is requested to contact the undersigned.

Respectfully submitted,

Date: 22 Dec 06

By: 
Daniel J. Noblitt
Reg. No. 35,969

NOBLITT & GILMORE, LLC
4800 North Scottsdale Road
Suite 6000
Scottsdale, Arizona 85251
Telephone: 480.994.9859
Facsimile: 480.994.9025

Substitute for form 1449/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1

of 8

Complete if Known

Application Number	10/730,388
Filing Date	December 07, 2003
First Named Inventor	Buxton
Art Unit	2863
Examiner Name	KHUU, CINDY
Attorney Docket Number	TAI,0800

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		APPLEWHITE. The view from the top. IEEE Spectrum, 41(11 (INT)):18-31, Nov 2004.	
		Canuto, M. Fairhurst and G. Howells, (2001) Improving ARTMap learning through variable vigilance. International Journal of Neural Systems, Vol. 11, No. 8, pp. 509-522.	
		Carpenter, G. A. and S. Grossberg, (1998) The ART of adaptive pattern recognition by self-organization neural network. Computer, vol. 21, no. 3, pp. 77-88.	
		K. Chang and J. Ghosh. Prindpal Curve Classifier – A nonlinear approach to pattern classification. in IEEE World Congress on Computational Intelligence, Neural... May1998	
		M. Clerc and J. Kennedy. The particle swarm - explosion, stability, and convergence in a multidimensional complex space. IEEE Transaction on Evolutionary Computation, Feb 2002	
		R. C. Eberhart and J. Kennedy, "A new optimizer using particle swarm theory", in Proc. 6th Intl. Symposium on Micro Machines and Human Science, Nagoya, Japan, IEEE 1995	
		R. C. Eberhart and Y. Shi. Evolving Artificial Neural Networks. In International Conference on Neural Networks and Brain, pages PL5 – PL13, Beijing, P.R. China, 1998	
		R. C. Eberhart and X. Hu, "Human Tremor analysis using particle swarm optimization", in Proc. Congress on Evolutionary Computation 1999, IEEE Service Center, pp 1927-1930	
		R.C. Eberhart and Y. Shi, "Comparing inertia weight and constriction factors in particle swarm optimization", in Proc. of the Congress of Evolutionary Computation, 2000	
		F. Chen and S. Liu, "A Neural-Network Approach To Recognize Defect Spatial Pattern in Semiconductor Fabrication", IEEE Transactions on Semiconductor Manufacturing.v.13 2000	

Examiner Signature	Date Considered
--------------------	-----------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.95. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.

PTO/SB/068 (09-06)
Approved for use through 03/31/2007. OMB 0651-0051
U.S. Patent and Trademark Office, U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449/PTO

Complete if Known

INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>	Application Number	10/730,388
	Filing Date	December 07, 2003
	First Named Inventor	Buxton
	Art Unit	2863
	Examiner Name	KHUU, CINDY
	Attorney Docket Number	TAI.0800

Sheet 2 of 8

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		T. Fountain, T. Dietterich, and B. Sudyka. Mining IC test data to optimize VLSI testing, the 6th ACM SIGKDD International Conference pages 18-25, 2000	
		N. Franken and A.P. Engelbrecht. Comparing PSO structures to learn the game of checkers from zero knowledge. In Congress on Evolutionary Computation, volume 1, Dec 2003	
		F. van den Bergh and A. P. Engelbrecht. "Cooperative Learning in Neural Networks using Particle Swarm Optimizers", South African Computer Journal, pp. 84-90, Nov. 2000	
		F. van den Bergh and A. P. Engelbrecht, "Training Product Unit Networks using Cooperative Particle Swarm Optimisers", in Proceedings of IJCNN 2001, (Washington DC, USA), 2001	
		K. W. Tobin, S. S. Gleason, T. P. Karnowski, S. L. Cohen and F. Lakhani, Automatic Classification of Spatial Signatures on Semiconductor Wafermaps, SPIE 22nd Annual (1997)	
		S.S. Gleason, K.W. Tobin, T.P. Karnowski, and Fred Lakhani, (1999) Rapid Yield Learning through Optical Defect and Electrical Test Analysis, SPIE, 1999	
		Hu M. K. "Visual pattern recognition by moments invariants", IRE Transactions on Information Theory, Vol. 8(2), pp. 179-187, 1962	
		The National Technology Roadmap for Semiconductors, Semiconductor Industry Association, San Jose, 2001 (Executive Summary)	
		The National Technology Roadmap for Semiconductors, Semiconductor Industry Association, San Jose, 2001 (Test and Test Equipment)	
		K. Kameyama, and Y. Kosugi, "Semiconductor Defect Classification using Hyperellipsoid Clustering Neural Networks and Model Switching", Intl Joint Conf on Neural Networks 1999	

Examiner Signature	Date Considered
---------------------------	------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Includes copy of this form with next communication to applicant.
 1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.
 This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.

Substitute for form 1449/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 3

of 8

Complete If Known

Application Number	10/730,388
Filing Date	December 07, 2003
First Named Inventor	Buxton
Art Unit	2863
Examiner Name	KHUU, CINDY
Attorney Docket Number	TAI.0800

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.†	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		T.P. Kamowski, K.W. Tobin, S.S. Gleason, Fred Lakhani, "The Application of Spatial Signature Analysis to Electrical Test Data: Validation Study," SPIE 24th Ann'l Symp Feb 1999	
		J. Kennedy and R. Mendes. Population structure and particle swarm performance. In Congress on Evolutionary Computation, pages 1671-1676, 2002.	
		J. Kennedy and R. Mendes. Neighborhood topologies In fully-informed and best-of-neighborhood particle swarms. IEEE Int'l Workshop on Soft Computing Jul 2003	
		Kohonen T., The self-organizing map. Proceedings of the IEEE 78, pp. 1464-1480, 1990	
		Kveton and D. Dash. Automatic excursion detection In manufacturing: Preliminary results. 18th Int'l Florida Artificial Intelligence Research Conference May 2004	
		Lanzi, P. L., "Fast Feature Selection with Genetic Algorithms: A Filter Approach", IEEE International Conference on Evolutionary Computation , 13-16 April 1997, pp. 537-540	
		Leonardis and H. Bischof, "An efficient MDL-based construction of RBF networks", Neural Networks, vol. 11, pp963-973, 1998	
		Y. Liu, X. Yao and T. Higuchi, "Evolutionary Ensembles with Negative Correlation Learning", in IEEE Transactions on Evolutionary Computation, 4(4): 380-387, Nov. 2000	
		R. Mendes, J. Kennedy, and J. Neves. Watch thy neighbor or how the swarm can learn from its environment. IEEE Swarm Intelligence Symposium, pages 88 - 94, April 24-26 2003	
		R. Mendes, J. Kennedy, and J. Neves. The Fully Informed Particle: Simpler, Maybe Better. IEEE Transaction on Evolutionary Computation, 8:204-210, June 2004	

Examiner
Signature

Date
Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

† Applicant's unique citation designation number (optional). ‡ Applicant is to place a check mark here if English language Translation is attached.
This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.

Substitute for form 1449/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet 4

of 8

Complete if Known

Application Number	10/730,368
Filing Date	December 07, 2003
First Named Inventor	Buxton
Art Unit	2863
Examiner Name	KHUU, CINDY
Attorney Docket Number	TAI.0800

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		MIGUELANEZ, EMILIO, DIWA: Device Independent Wafermap Analysis, 2003	
		MIGUELANEZ, EMILIO, DIWA: Device Independent Wafermap Analysis, 2003 (PRESENTATION)	
		MIGUELANEZ, EMILIO, Automating the Analysis of Wafer Data Using Adaptive Resonance Theory Networks, 2004 (PRESENTATION)	
		MIGUELANEZ, EMILIO, Evolving Neural Networks using Swarm Intelligence for Binmap Classification, 2004	
		MIGUELANEZ, EMILIO, Automating the Analysis of Wafer Data Using Adaptive Resonance Theory Networks, 2004	
		MIGUELANEZ, EMILIO, Evolving Neural Networks using Swarm Intelligence for Binmap Classification, 2004 (PRESENTATION)	
		MIGUELANEZ, EMILIO, Swarm Intelligence in Automated Electrical Wafer Sort Classification, 2005	
		T. Nakashima, G. Nakai, and H. Ishibuchi. Constructing fuzzy ensembles for pattern classification problems. IEEE Int'l Conf on Systems, Man and Cybernetics, October 2003	
		Nab'lett. The role of test in total quality management. In Proceedings of the IEEE Systems Readiness Technology Conference AUTOTESTCON'94, volume 1, pages 727-735, sep 1994	
		Ozcan and C.K. Mohan. Particle swarm optimization: Surfing the waves. In International Congress on Evolutionary Computation, pages 1939-1944, 1999	

Examiner Signature	Date Considered
--------------------	-----------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 509. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached. This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1480, Alexandria, VA 22313-1480.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-785-9195) and select option 2.

Substitute for form 1449/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet

5

of

8

Complete If Known

Application Number	10/730,388
Filing Date	December 07, 2003
First Named Inventor	Buxton
Art Unit	2863
Examiner Name	KHUU, CINDY
Attorney Docket Number	TAI.0800

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.†	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		K. E. Parsopoulos and M. N. Vrahatis. On the Computation of All Global Minimizers through Particle Swarm Optimization. IEEE Transaction on Evolutionary Computation, June 2004.	
		T. Poggio and F. Girosi, "Networks for approximation and learning", Proc. of the IEEE, vol. 78, pp1481-197, 1990	
		J. Salerno, "Using the particle swarm optimization technique to train a recurrent neural model", IEEE Inter. Conference on Tools with Artificial Intelligence, pp 45-49, 1997	
		Y. Shi and R.C. Eberhart, "Parameter selection in particle swarm optimization", in Proc. of the 1998 Annual Conference on Evolutionary Programming, San Diego, CA, 1998	
		Y. Shi and R. C. Eberhart, "A Modified Particle Swarm Optimizer", in Proc. of Intl. Joint Conf. on Neural Networks, Washington, USA, pp. 69-73, July 1999	
		K. W. Tobin, S. S. Gleason, T. P. Karnowski, An Image Paradigm for Semiconductor Defect Data Reduction, SPIE's International Symposium on Microlithography, 1996	
		K.W. Tobin, S.S. Gleason, F. Lakhani, and M.H. Bennet, "Automated Analysis for Rapid Defect Sourcing and Yield Learning", Future Fab International, Vol. 4, 1997	
		K.W. Tobin, S. S. Gleason, T.P. Karnowski, and S.L. Cohen, Feature Analysis and classification of Manufacturing Signatures on Semiconductor Wafers, SPIE 9th Annual, 1997	
		K. W. Tobin, S. S. Gleason, T. P. Karnowski, S. L. Cohen and F. Lakhani, Automatic Classification of Spatial Signatures on Semiconductor Wafermaps, SPIE 22nd Annual, 1997	
		Tseng, L. Y. and Yang, S. B., "Genetic Algorithms for Clustering, Feature Selection and Classification", International Conference on Neural Networks, 9-12 June 1997	

Examiner
Signature

Date
Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

† Applicant's unique citation designation number (optional). 2. Applicant is to place a check mark here if English language Translation is attached. This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 36 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-785-9195) and select option 2.

Substitute for Form 1449/PTO		Complete If Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	10/730,388
		Filing Date	December 07, 2003
		First Named Inventor	Buxton
		Art Unit	2863
		Examiner Name	KHUU, CINDY
		Attorney Docket Number	TAI.0800
Sheet 6	of 8		

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		Vafaie, H. and De Jong, K., "Genetic Algorithms as a Tool for Feature Selection in Machine Learning", 4th Int'l Conf on Tools with Artificial Intelligence, Nov. 1992	
		Watkins and L. Boggess. A new classifier based on resource limited Artificial Immune Systems. In Congress on Evolutionary Computation CEC'02, vol II, pp 1546-51. IEEE May 2002	
		C. Zhang, H. Shao, and Y. Li, "Particle swarm optimization for evolving artificial neural networks", IEEE Int'l Conf on Systems, Man and Cybernetics vol. 4, 2000	

Examiner Signature	Date Considered
---------------------------	------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 509. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.
 1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.
 This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.

Complete if Known

Application Number	10/730,388
Filing Date	December 07, 2003/388
First Named Inventor	Buxton
Art Unit	2863
Examiner Name	KHUU, CINDY
Attorney Docket Number	TAI 0800

(Use as many sheets as necessary)

Sheet	7	of	8	Attorney Docket Number	TAI.0800
-------	---	----	---	------------------------	----------

[illegible]

Examiner
Signature

Date Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Covered: Individual or entity who has been identified by the U.S. Patent and Trademark Office as being involved in the preparation, filing, prosecution, or maintenance of a patent application. This collection of information is required by 37 CFR 1.986. The information is provided to obtain or retain a benefit by the public which is to file (and/or the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application to the USPTO. If you are unable to complete this form, please contact the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Complete if Known

Application Number	10/730,388
Filing Date	December 07, 2003
First Named Inventor	Buxton
Art Unit	2863
Examiner Name	KHUU, CINDY
Attorney Docket Number	TAI.0800

Sheet	8	of	8
-------	---	----	---

U. S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

Examiner Signature	Date Considered
--------------------	-----------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. * Applicant's unique citation designation number (optional). ** See Kinda Codes of USPTO Patent Documents at www.uspto.gov/patents/USPTO/PatentDocuments.htm. *** Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). * For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. (Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible). * Applicant is to place a check mark here if English language is not applicable.

Translation is attached.
This collection of information is required by 37 CFR 1.87 and 1.88. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is guaranteed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting a completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you need to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND COMMENTS TO: Chief Patent, R.O. Box 1450, Alexandria, VA 22313-1450.

TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.